

1986  
IEEE—MTT-S  
International Microwave  
Symposium  
Digest

June 2-4, 1986  
Convention Center  
Baltimore, Maryland



*Publications Chairman*  
C. R. Westgate



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IEEE Catalog No. 86CH2301-0

ISSN 0149-645X

Library of Congress Catalog No. 77-645125

***IEEE MTT-S International Microwave Symposium***

IEEE MTT-S International Microwave Symposium Digest 1977  
New York, Institute of Electrical and Electronics Engineers

v. III. 28 cm. annual.

Continues: IEEE MTT-S International Microwave Symposium Digest of technical papers, ISSN 0149-6298.

Key title: IEEE MTT-S International Microwave Symposium Digest, ISSN 0149-645X

1. Microwaves—Congresses. 2. Microwave devices—Congresses. I. Institute of Electrical and Electronics Engineers. II. IEEE MTT-S International Microwave Symposium Digest.

TK7876.I184  
Library of Congress

621.381'3  
78

77-645125  
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